Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/650,430	CHEN, CHIH-WEI
Examiner	Art Unit
Justin Knapp	2182

	SEARCHED				
Class	Subclass	Date	Examiner		
710	36	4/6/05	X		
	19				
	301				
	302				
4	302 72	7	1		
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Subclass	Date	Examiner
	Subclass	Subclass Date

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST search	416/05		